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EMC IC modelling –

Part 2: Models of integrated circuits for EMI behavioural simulation – Conducted emissions modelling (ICEM-CE)

Modèles de circuits intégrés pour la CEM –

Partie 2: Modèles de circuits intégrés pour la simulation du comportement lors de perturbations électromagnétiques – Modélisation des émissions conduites (ICEM-CE)



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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
Fax: +41 22 919 03 00
info@iec.ch
www.iec.ch

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EMC IC MODELLING –

Part 2: Models of integrated circuits for EMI behavioural simulation – Conducted emissions modelling (ICEM-CE)

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International Standard IEC 62433-2 has been prepared by subcommittee 47A: Integrated Circuits, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2008. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

Incorporation of an XML based exchange format for model representation.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/999/FDIS	47A/1007/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62433 series, published under the general title *EMC IC modelling*, can be found on the IEC website.

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EMC IC MODELLING –

Part 2: Models of integrated circuits for EMI behavioural simulation – Conducted emissions modelling (ICEM-CE)

1 Scope

This part of IEC 62433 specifies macro-models for an Integrated Circuit (IC) to simulate conducted electromagnetic emissions on a printed circuit board. The model is commonly called Integrated Circuit Emission Model – Conducted Emission (ICEM-CE).

The ICEM-CE macro-model can also be used for modelling an IC-die, a functional block and an Intellectual Property (IP) block.

The ICEM-CE macro-model can be used to model both digital and analogue ICs.

Basically, conducted emissions have two origins:

- conducted emissions through power supply terminals and ground reference structures;
- conducted emissions through input/output (I/O) terminals.

The ICEM-CE macro-model addresses those two types of origins in a single approach.

This standard defines structures and components of the macro-model for EMI simulation taking into account the IC's internal activities.

This part of IEC 62433 has two main parts:

- the first is the electrical description of ICEM-CE macro-model elements along with the specific requirements for information.
- the second part proposes a universal data exchange format called CEML based on XML. This format allows encoding the ICEM-CE in a more useable and generic form for simulating the conducted emissions.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC TS 62433-1:2011, *EMC IC modelling – Part 1: General modelling framework*

CISPR 17, *Methods of measurement of the suppression characteristics of passive EMC filtering devices*

3 Terms, definitions, abbreviations and conventions

3.1 Terms and definitions

For the purposes of this document, the following terms and definitions apply.